## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of Lu et al.

Serial No. Not yet assigned
Filed July 21, 2003

Confirmation No. Not yet assigned
For METHOD TO MONITOR AND CONTROL THE CRYSTAL COOLING OR
OUENCHING RATE BY MEASURING CRYSTAL SURFACE TEMPERATURE

July 21, 2003

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## INFORMATION DISCLOSURE STATEMENT

In accordance with 37 C.F.R. 1.97 and 1.98 and MPEP 609, and in compliance with the duty of disclosure set forth in 37 C.F.R. 1.56, applicants submit copies of the references listed on the attached PTO/SB/08A for consideration by the Patent and Trademark Office in the above-entitled application and to be made of record therein.

Respectfully submitted,

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PTO/SB/08A				Complete if Known		
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s	TATEMENT B	Y AP	PLICANT	Filing Date	July 21, 2003	
(use	e as many shee	ets as	necessary)	Confirmation Number	Not yet assigned	
				First Named Inventor	Zheng Lu	
				Group Art Unit	Not yet assigned	
				Examiner Name	Not yet assigned	
Sheet	1	of	1	Attorney Docket No.	MEMC 02-0400 (3053)	

U.S. PATENT DOCUMENTS								
-		U.S. Patent Docume	nt		Date of Publication of Cited Document MM-DD-YYYY			
Examiner Initials*	Cite No.1	Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document				
	1	5,178,720		Frederick	01/12/1993			
	2	5,653,799		Fuerhoff	08/05/1997			
	3	5,665,159		Fuerhoff	09/09/1997			
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	6	6,503,322	B1	Schrenker et al.	01/07/2003			

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l	Examiner	Date	-
1	Signature	Considered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Unique citation designation number. <sup>2</sup>See attached Kinds of U.S. Patent Documents. <sup>3</sup>Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document, <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup>Applicant is to place a check mark here if English language Translation is attached or place an "A" here if English language abstract is attached..